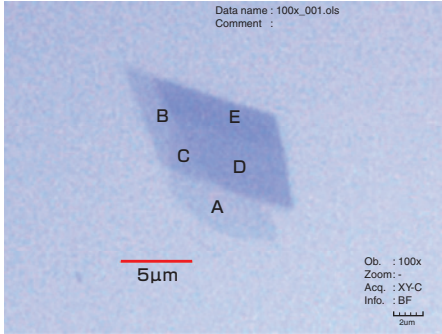


グラフェンの厚さ計測

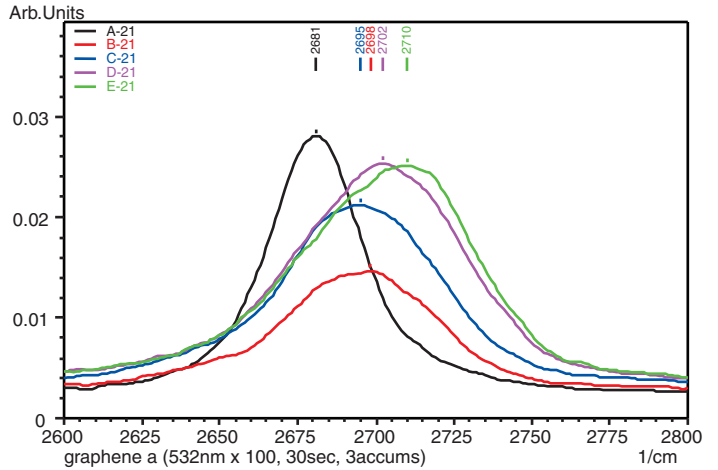
Thickness measurement of graphene by Raman spectrometry and SPM

単層グラフェンと多層グラフェンのラマンスペクトル/Raman spectra of graphene and graphene multilayer

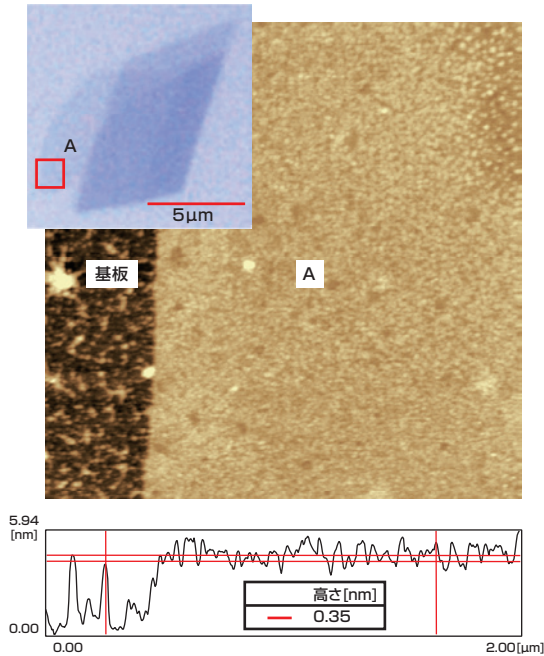


光学顕微鏡像
Optical microscope image

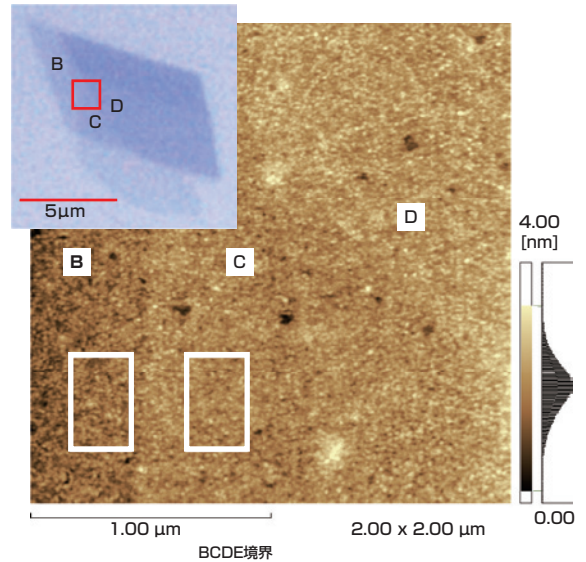
A graphene monolayer
B~E graphene multilayer



グラフェンシート境界部でのSPM段差計測/Step measurement of the boundary of graphene sheet by SPM



単層グラフェンシート段差計測
Topographic image and profile analysis
between substrate and graphene A



平均段差:0.363[nm] 面積A:0.10[μm²] 面積B:0.10[μm²]

グラフェンシート B と C の境界部のSPM 形状像と平均段差計測
SPM topographic image of graphene B and C
in boundary part and average step measurement

試料ご提供: 株式会社富士通研究所 ナノエレクトロニクス研究センター
Materials supplied by Nanoelectronics Research Center, FUJITSU LABORATORIES LTD..